

Notice of References Cited

Application/Control No.

10/561,830

Applicant(s)/Patent Under
Reexamination
HAYASHI ET AL.

Examiner

Ponder N. Thompson-Rummel

Art Unit

1753

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0110085	06-2004	Iwai et al.	430/270.1
*	B	US-2004/0029037	02-2004	Kamabuchi et al.	430/270.1
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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